

Search Notes				Application/Control No.	Applicant(s)/Patent under Reexamination
				10/635,916	SWAINE ET AL.
				Examiner	Art Unit
				Hien X. Vo	2863

SEARCHED			
Class	Subclass	Date	Examiner
702	176	4/15/2005	VXH
	177		
	178		
	187		
711	162		
	154		
717	124		
	128		
714	45		
<u>UPDATE SEARCH</u>			
ABOVE			
1/28/06 VXH			
<u>UPDATE SEARCH ABOVE</u>			
2/28/06 VXH			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PLus search	3/9/2005	VXH
EAST	4/13/2005	
East Interference search 902/176-178 /187	2/28/06	VXH
717/124/128 714/45 SEE PRINT OUT		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
702	176	2/28/06	VXH
	177		
	178		
	187		
717	124	128	
714	45		